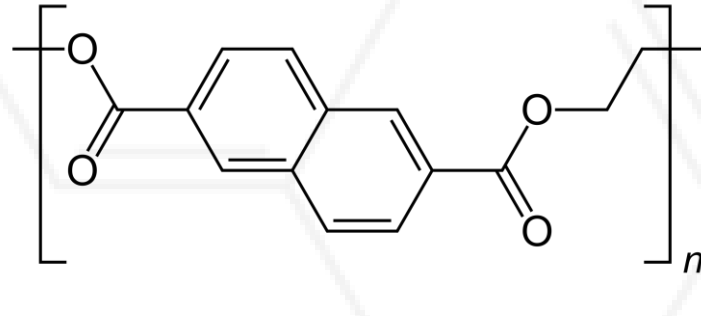


# Development & Characterization of a PEN-based Wavelength Shifting Reflector

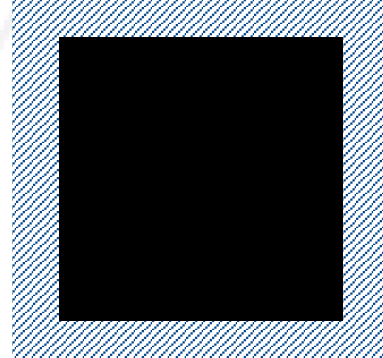
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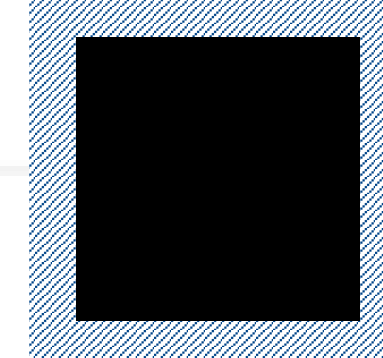
## Polyethylene Naphthalate (PEN)




- Organic wavelength shifter (WLS) with quantum efficiency  $\geq 49\%$  (90% CL) [1]
- PEN foils studied:
  - Thickness: 25  $\mu\text{m}$ , 50  $\mu\text{m}$ , 125  $\mu\text{m}$
  - Production grade: Q51, Q53
  - Surface: smooth, sanded
- Reflectors (R) types used: ESR, Tetratex, Tyvek
- Optically coupled or uncoupled



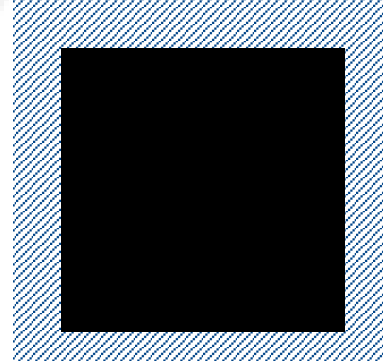
ESR



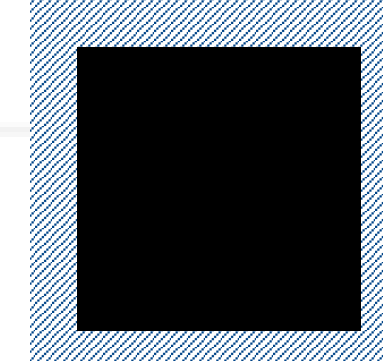
Tetratex



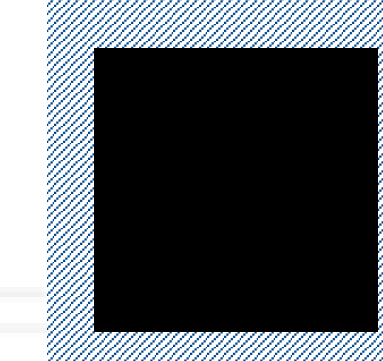
Tyvek



25  $\mu\text{m}$  smooth



25  $\mu\text{m}$  sanded

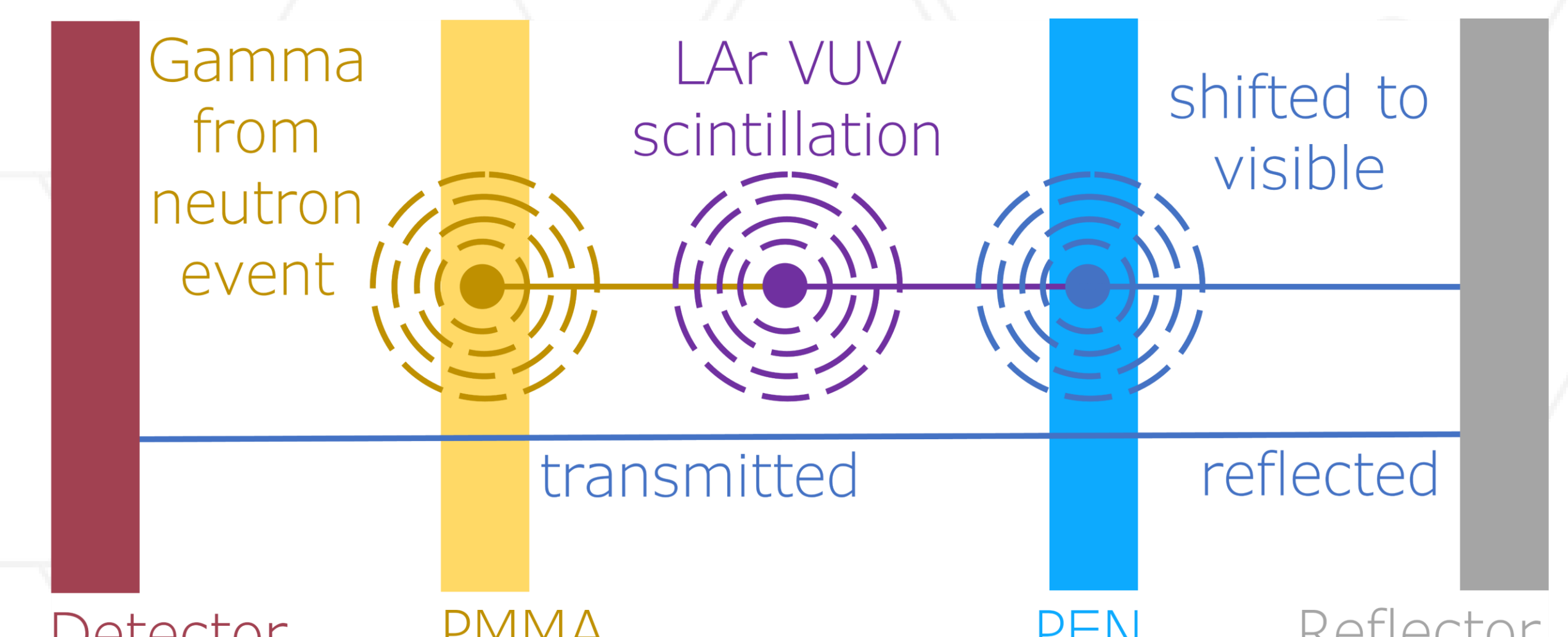


PEN-Laminate

[1] G. R. Araujo, et al., Eur. Phys. J. C, 82(5):442, 2022, arXiv:2112.06675.

## PEN-based WLSR in Rare-Event Searches

- Large-scale liquid argon (LAr) volumes for rejection of neutron background
- Covering  $\sim 100 \text{ m}^2$  of optically inactive surfaces with PEN-based WLSR for increased veto efficiency
- PEN scalable alternative to commonly used WLSs



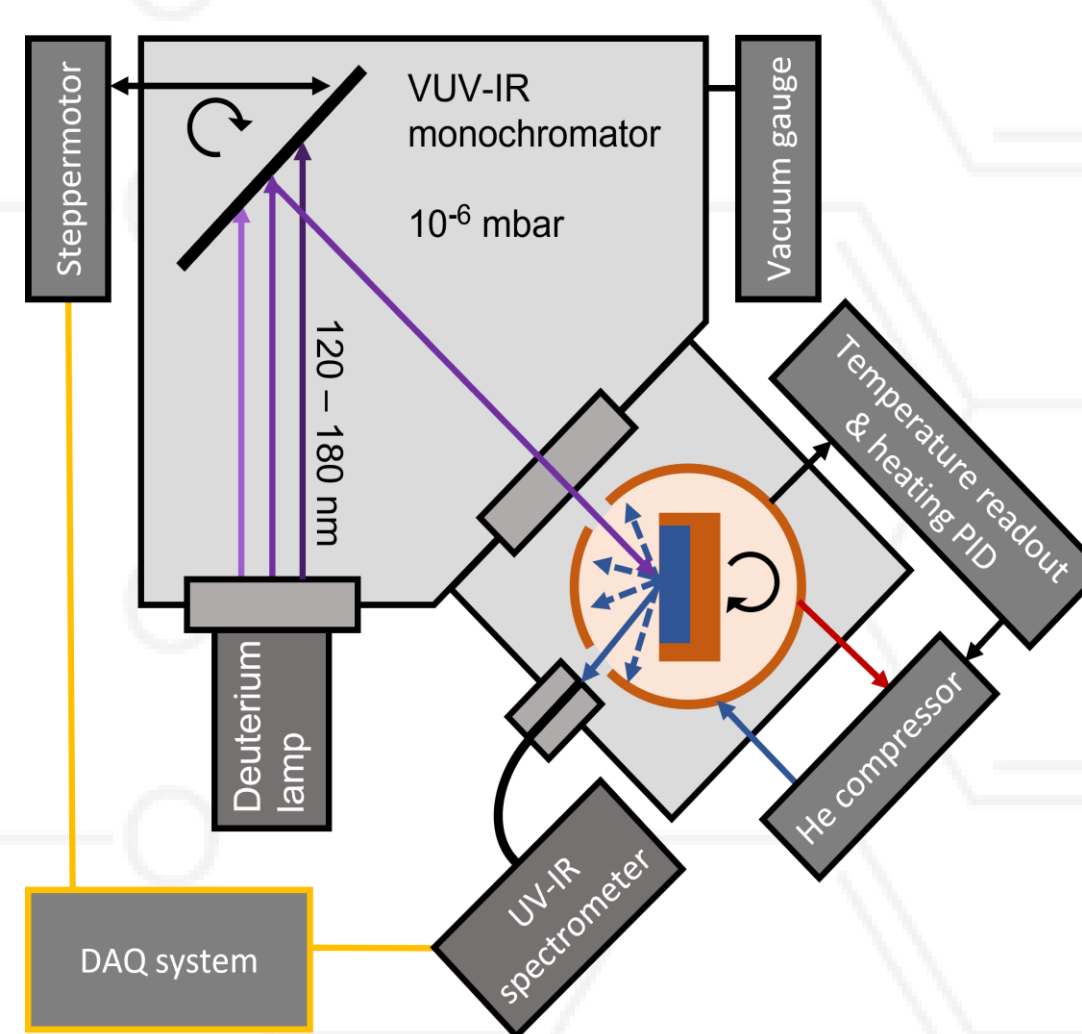
Gamma from neutron event → LAr VUV scintillation → shifted to visible

Detector | PMMA | PEN | Reflector

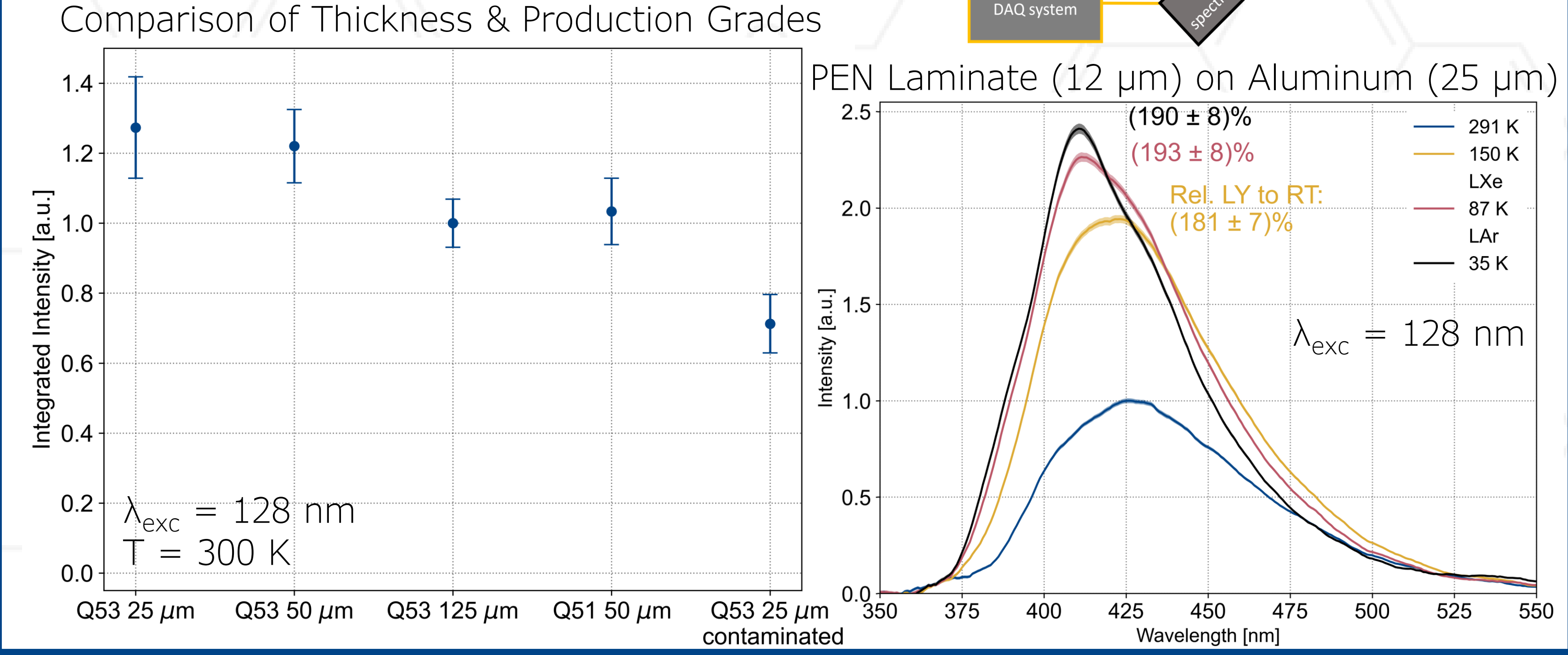
transmitted | reflected

## Spectra & Relative Efficiency of PEN Foils

- Excitation by 128 nm (LAr scintillation wavelength)
- Temperature: 300 K - 35 K
- Highest relative efficiency for 25  $\mu\text{m}$  foils and Q53 production grade



Staircase, VUV-IR monochromator (10<sup>-6</sup> mbar), Vacuum gauge, Temperature controller & heating PID, He compressor, LAr, Deuterium lamp, DAQ system, WLSR spectrometer



### LEGEND-1000

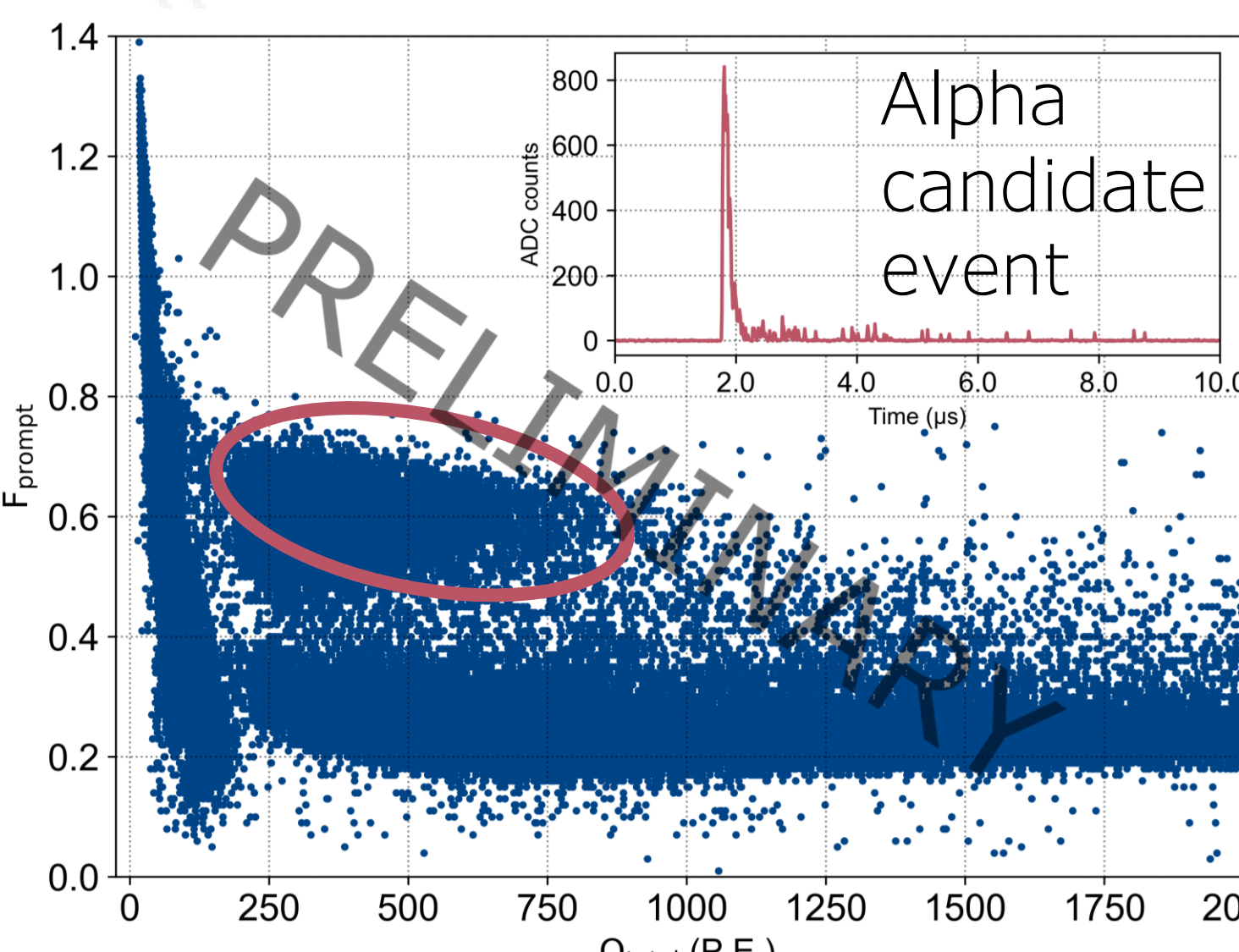
- Neutrinoless double-beta decay in <sup>76</sup>Ge
- Segmented LAr volumes lined with WLSRs

### DarkSide-20k

- Dark Matter WIMP Search
- Dual-Phase argon TPC
- Neutron Veto with Gd-loaded PMMA lined with ESR+PEN

## Stability of Large-scale PEN-based WLSR

- Validate light yield & light yield stability
- 4 m<sup>2</sup> of ESR+PEN Q53 25  $\mu\text{m}$



PRELIM

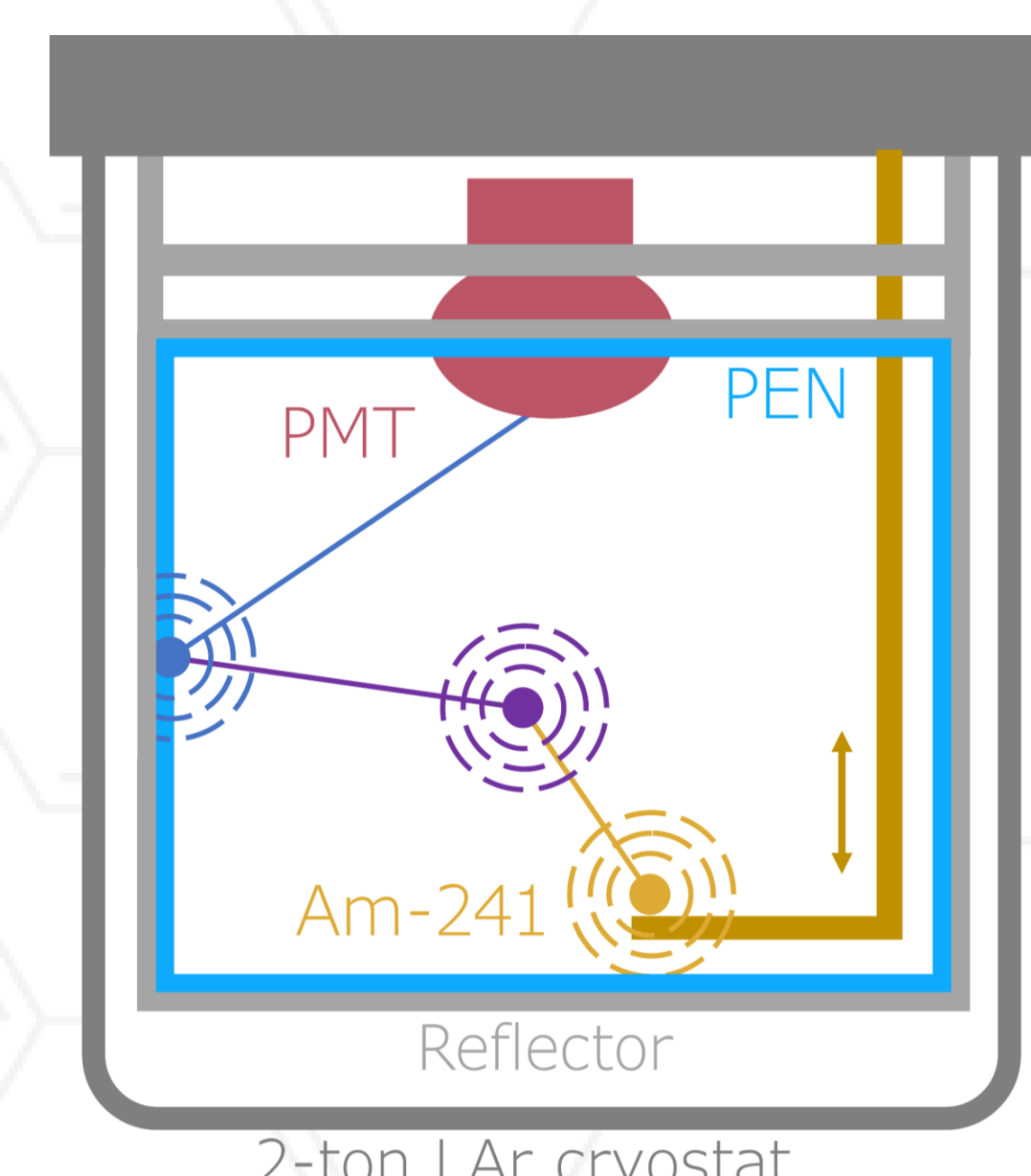
Alpha candidate event

ADC counts vs Time (μs)

800, 600, 400, 200, 0

0.0, 2.0, 4.0, 6.0, 8.0, 10.0

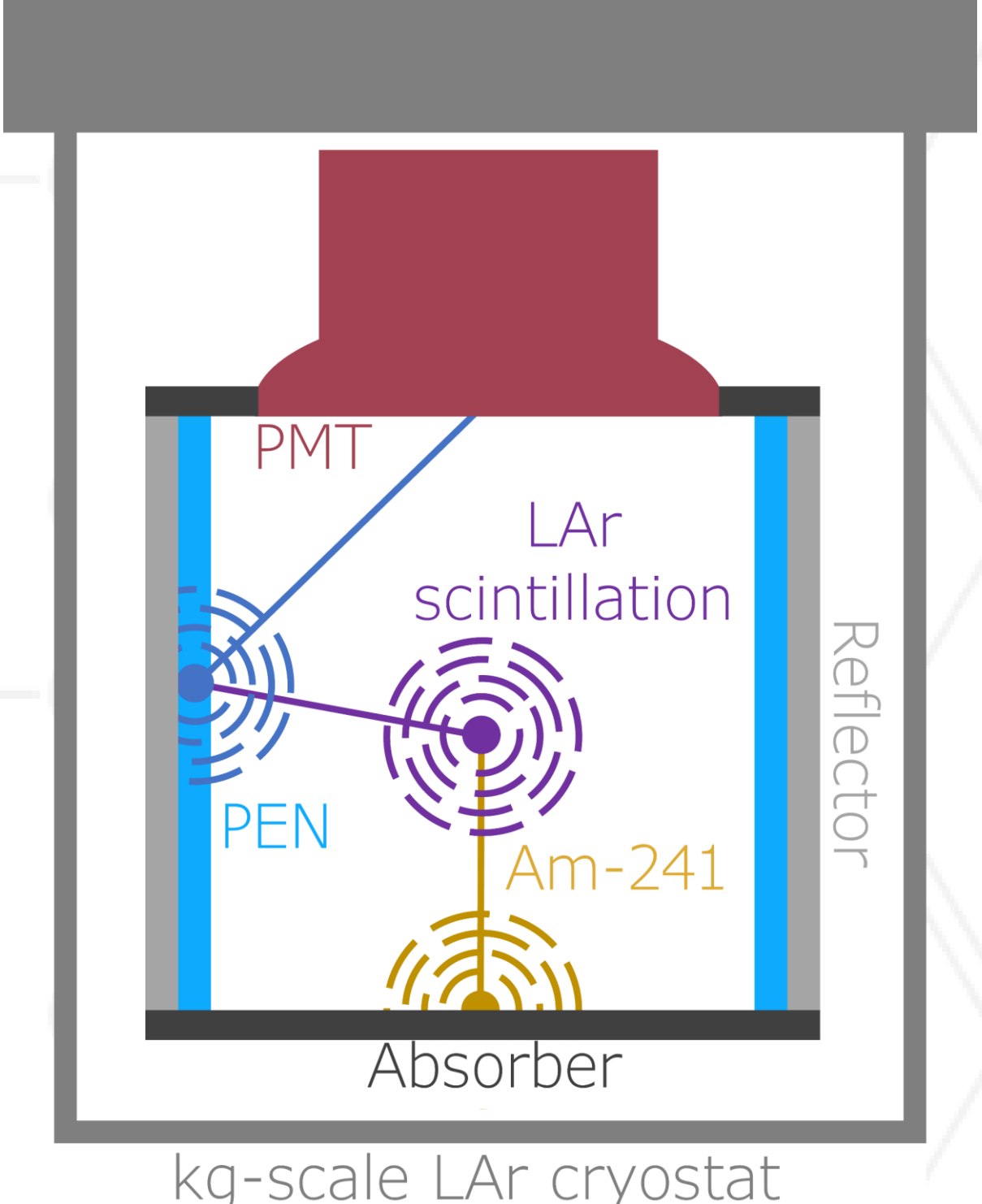
2-ton LAr cryostat



PMT, PEN, Am-241, Reflector

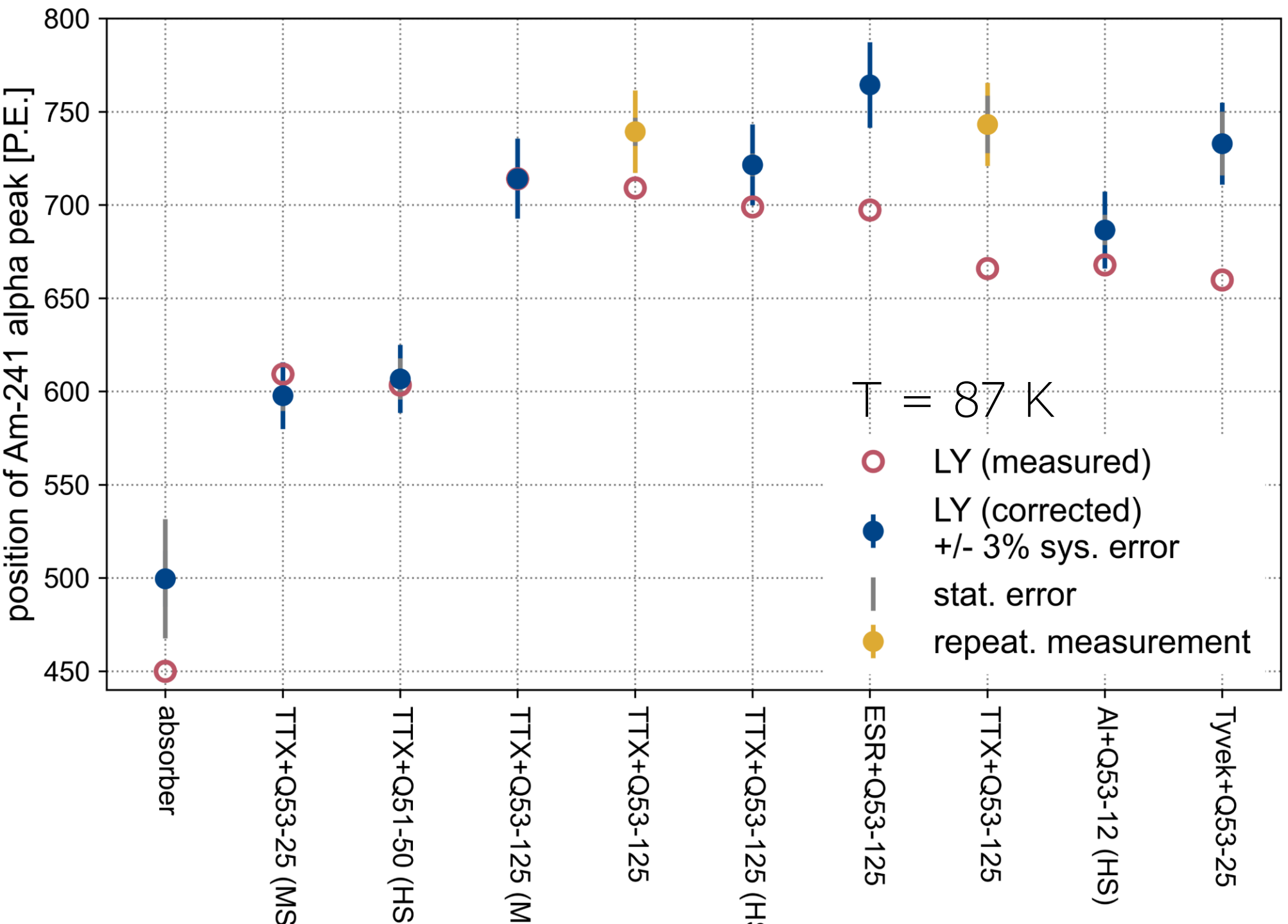
## Efficiency of PEN-based WLSRs in LAr

- 25  $\mu\text{m}$  films not optimally mounted due to weak structural integrity
- Identified no significant difference in light yield between surface finish and reflector used



PMT, LAr scintillation, Reflector, PEN, Absorber, Am-241

kg-scale LAr cryostat



position of Am-241 alpha peak [P.E.]

800, 750, 700, 650, 600, 550, 500, 450

absorber, TTX+Q53-25 (MS), TTX+Q51-50 (HS), TTX+Q53-125 (MS), TTX+Q53-125 (HS), ESR+Q53-125, TTX+Q53-125, A+Q53-12 (HS), Tyvek+Q53-25

$T = 87 \text{ K}$

- LY (measured)
- LY (corrected)  $\pm 3\%$  sys. error
- stat. error
- repeat. measurement

## ICP-MS of Commercial PEN Batch

- ICP-MS of insufficiently performing batch of PEN Teonex Q53 25  $\mu\text{m}$
- VUV-absorbing In and Zn contaminations found
- screening of optical performance before installation in experiments

Element	Contam. Batch [ppm]	Regular Batch [ppm]
Zn	4.1 $\pm$ 1.2	0.3 $\pm$ 0.1
In	15.4 $\pm$ 4.6	0.010 $\pm$ 0.003